ABTS-P™

Advanced **B**urn-In & **T**est **S**ystem

A high capacity system for test and burn-in of logic devices

System Benefits:

- True Per-pin Tester Architecture
  - ♦ 128 independent I/O channels per burn-in board
  - ♦ Per-pin voltage, timing, formatting and tri-state on-the-fly
  - ♦ 10MHz data rate, 20MHz clocks
- Very High System Capacity
  - ♦ Up to 72 burn-in board slots
  - ♦ Up to 36 pattern zones to handle small lots
  - ♦ 15KW chamber dissipation
  - ♦ Small system footprint
  - ♦ No side access required
- Low Cost of Ownership
  - ♦ Cost Effective Burn-in Boards (only edge fingers, no costly connectors, cost effective size)
  - ♦ Highly efficient power delivery
  - ♦ Low-power standby mode

ABTS BIB

"Changing the Way ICs Are Tested"

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